

N-Channel Enhancement Mode MOSFET

1. Product Information

Features

- High Switching Speed
- Improved dv/dt capability

Applications

- High efficiency switch mode power supplies
- Electronic lamp ballasts based on half bridge
- LED power supplies

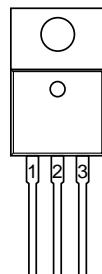
Quick reference

- $V_{DS} = 500 \text{ V}$
- $I_D = 20 \text{ A}$
- $R_{DS(ON)} \leq 280 \text{ m}\Omega @ V_{GS}=10 \text{ V}$ (Type: 260 mΩ)
- $Q_g @ \text{type} = 53 \text{ nC}$

Pin Description

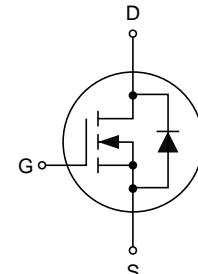
Pin	Description
1	Gate(G)
2	Drain(D)
3	Source(S)

Simplified Outline



Top View
TO-220

Symbol



Package Marking and Ordering Information

Product Name	Package	Marking	Reel Size	Tape Width	Quantity
KJ20N50C	TO-220	KJ20N50C	-	-	50 pcs/Tube

2. Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Values	Unit
V_{DS}	Drain-Source Voltage	500	V
V_{GS}	Gate-Source Voltage	± 30	V
I_D	Drain Current Continuous	20	A
I_{DM}	Pulsed Drain Current (note 2)	80	A
E_{AS}	Single Pulse Avalanche Energy (note 3)	1000	mJ
dV/dt	Peak Diode Recovery dV/dt	2.2	V/ns
P_D	Power Dissipation	200	W
T_J, T_{STG}	Operating Junction and Storage Temperature Range	-55~150	W/°C
$R_{θJA}$	Thermal Resistance-Junction to Ambient	62.5	°C/W
$R_{θJC}$	Thermal Resistance-Junction to Case	0.625	°C/W

Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature

3. $L = 21.5 \text{ mH}$, $I_{AS} = 5 \text{ A}$, $V_{DD} = 50 \text{ V}$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$

4. $I_{SD} \leq 5 \text{ A}$, $di/dt \leq 200 \text{ A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$

3. Electrical Characteristics ($T_C=25^\circ\text{C}$, unless otherwise noted)

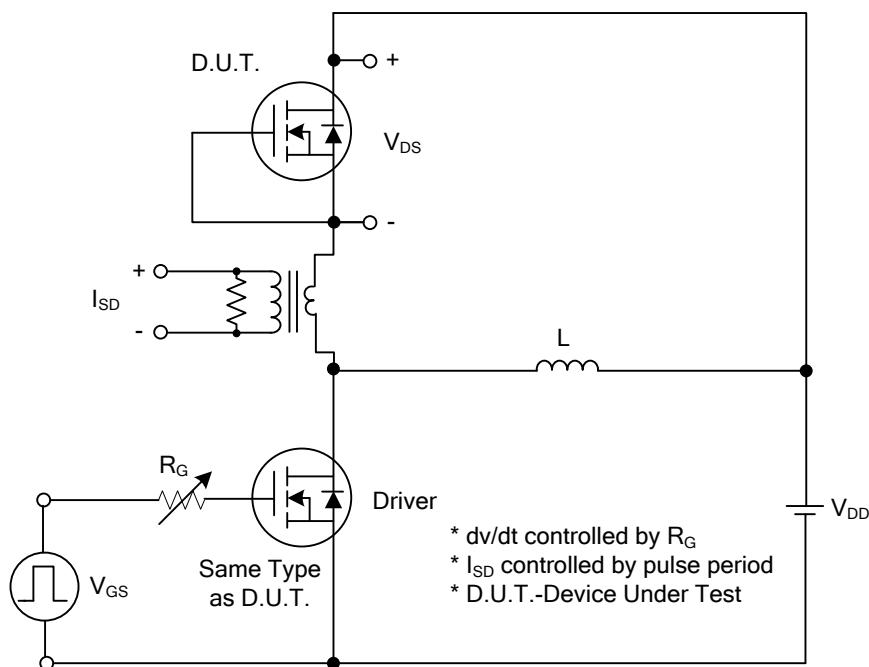
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0 \text{ V}, I_{\text{D}}=250 \mu\text{A}$	500	-	-	V
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=500 \text{ V}, V_{\text{GS}}=0 \text{ V}$	-	-	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{\text{DS}}=0 \text{ V}, V_{\text{GS}}=\pm 30 \text{ V}$	-	-	± 100	nA
$V_{\text{GS(th)}}$	Gate-Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250 \mu\text{A}$	2.0	-	4.0	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}}=10 \text{ V}, I_{\text{D}}=10 \text{ A}$	-	0.26	0.28	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0 \text{ V}, V_{\text{DS}}=25 \text{ V}, f=1.0 \text{ MHz}$	-	2450	-	pF
C_{oss}	Output Capacitance		-	275	-	
C_{rss}	Reverse Transfer Capacitance		-	16.5	-	
Q_g	Total Gate Charge	$V_{\text{DS}}=100 \text{ V}, V_{\text{GS}}=10 \text{ V}, I_{\text{D}}=20 \text{ A}, I_{\text{G}}=1 \text{ mA}$ (note 1,2)	-	53	-	nC
Q_{gs}	Gate-Source Charge		-	11	-	
Q_{gd}	Gate-Drain Charge		-	13	-	
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DD}}=100 \text{ V}, V_{\text{GS}}=10 \text{ V}, I_{\text{D}}=20 \text{ A}, R_{\text{G}}=25 \Omega$ (note 1,2)	-	32	-	ns
t_r	Turn-on Rise Time		-	30	-	
$t_{\text{d(off)}}$	Turn-off Delay Time		-	162	-	
t_f	Turn-off Fall Time		-	70	-	
I_s	Maximum Continuous Drain-Source Diode Forward Current	-	-	20	A	
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	-	-	80	A	
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}}=0 \text{ V}, I_s=20 \text{ A}$ (note 1)	-	-	1.4	V
t_{rr}	Reverse Recovery Time	$V_{\text{GS}}=0 \text{ V}, I_s=20 \text{ A}, dI/dt=100 \text{ A}/\mu\text{s}$ (note 1)	-	412	-	ns
Q_{rr}	Reverse Recovery Charge		-	6.5	-	μC

Note:

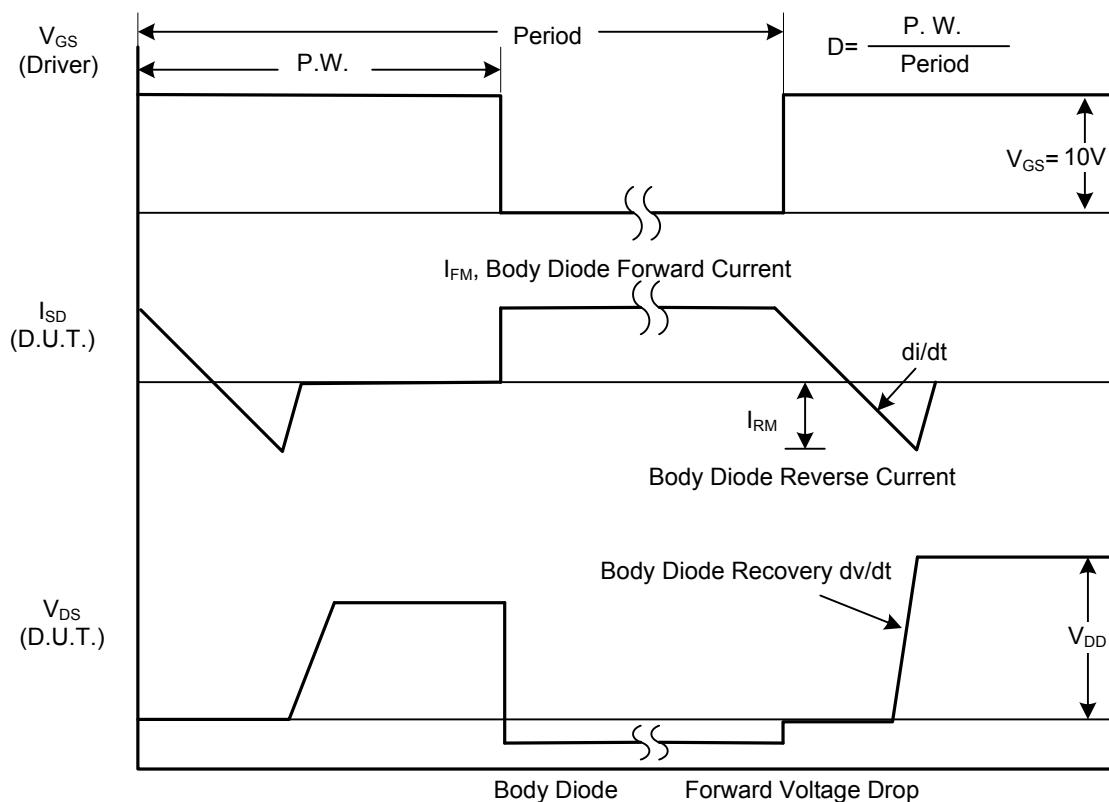
1. Pulse Test: Pulse width $\leq 300 \mu\text{s}$, Duty cycle $\leq 2\%$

2. Essentially independent of operating temperature.

4. Test Circuits and Waveforms

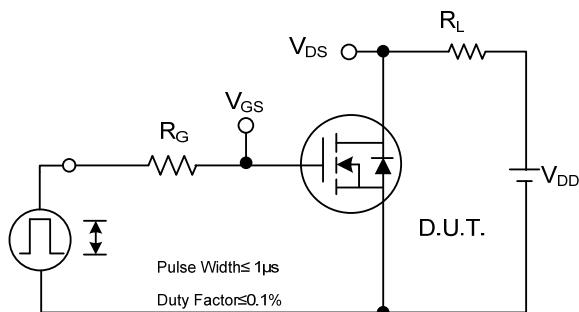


Peak Diode Recovery dv/dt Test Circuit

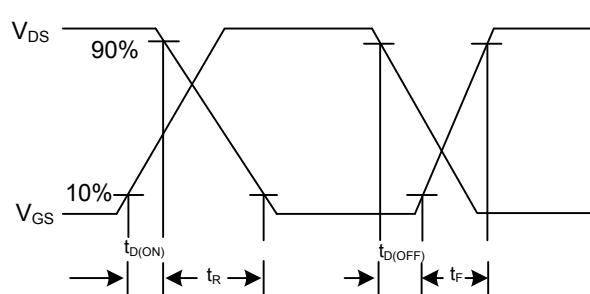


Peak Diode Recovery dv/dt Waveforms

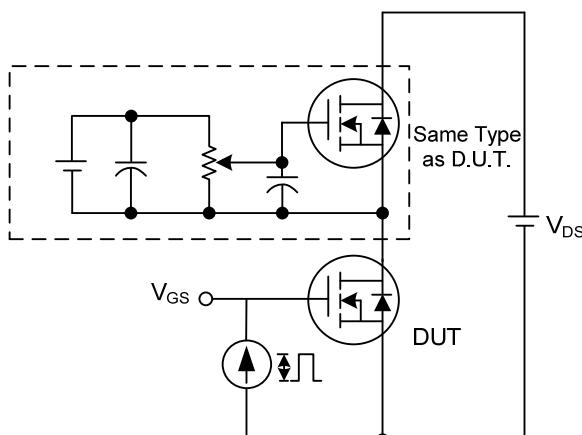
4. Test Circuits and Waveforms (Cont.)



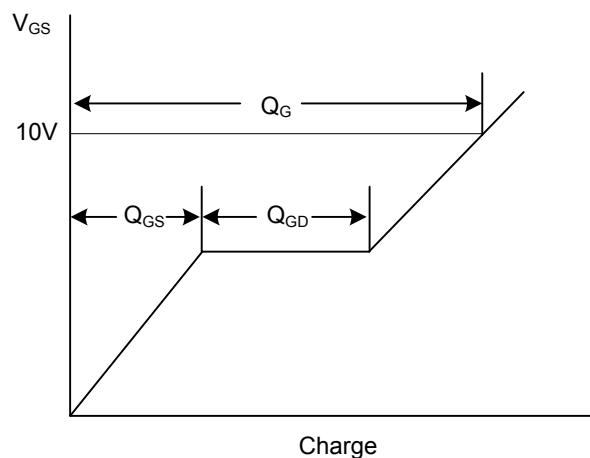
Switching Test Circuit



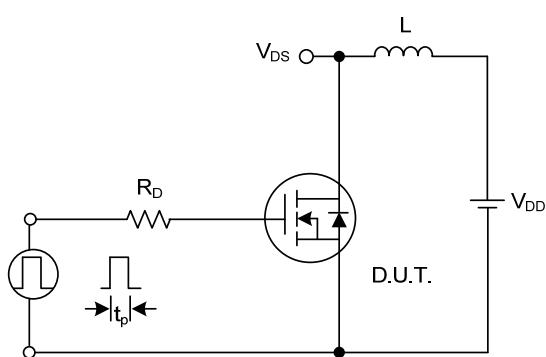
Switching Waveforms



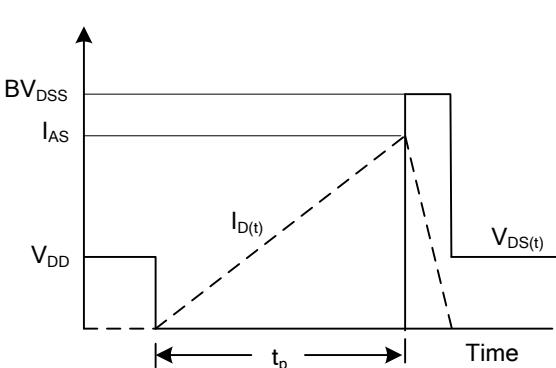
Gate Charge Test Circuit



Gate Charge Waveform

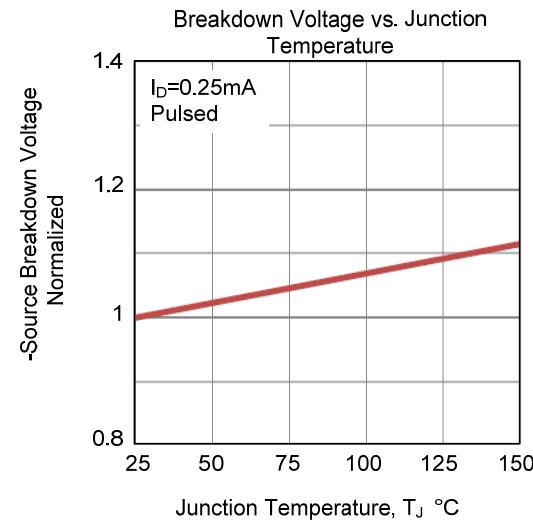
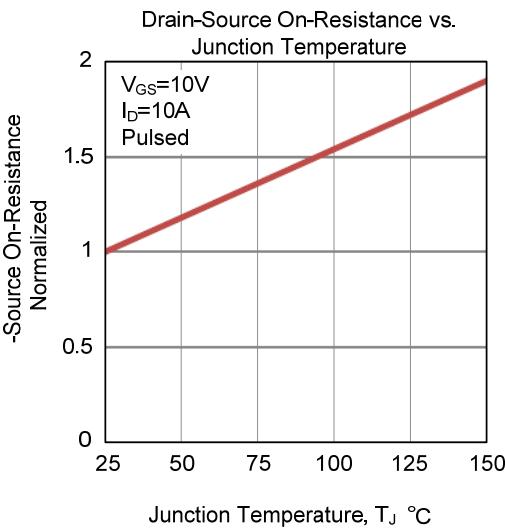
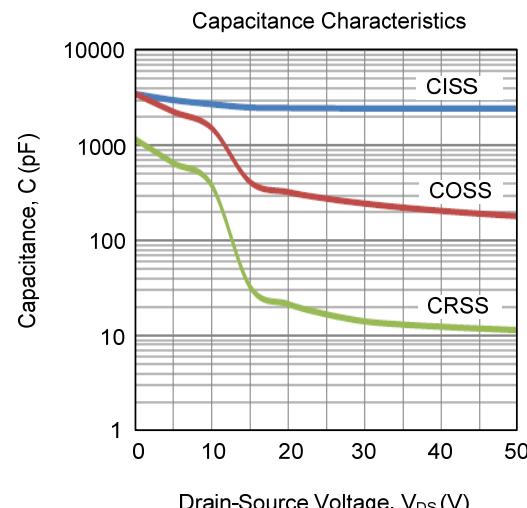
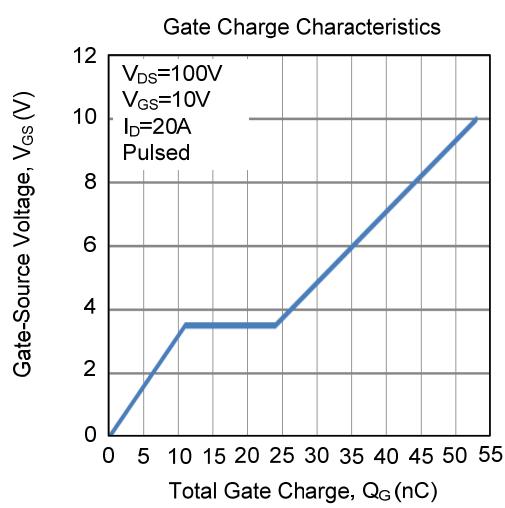
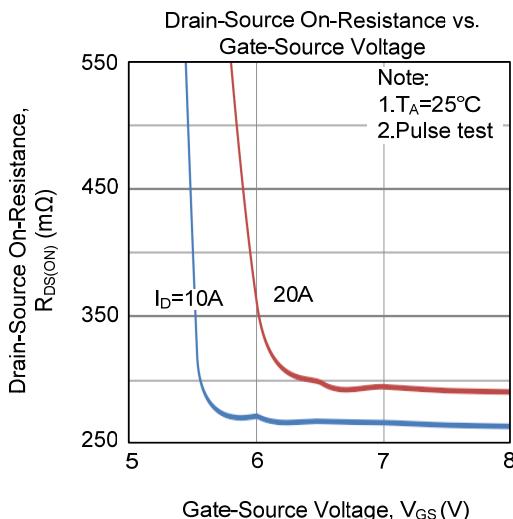
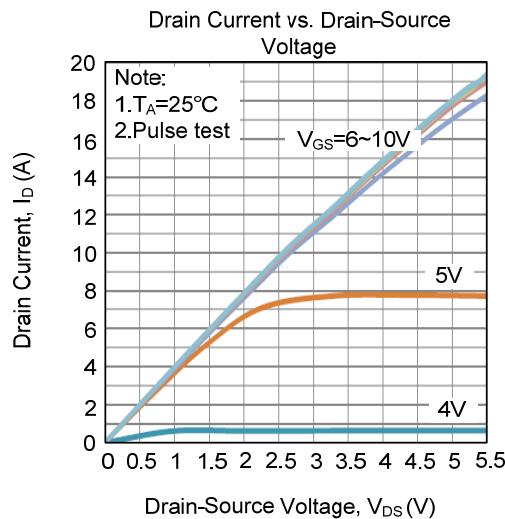


Unclamped Inductive Switching Test Circuit

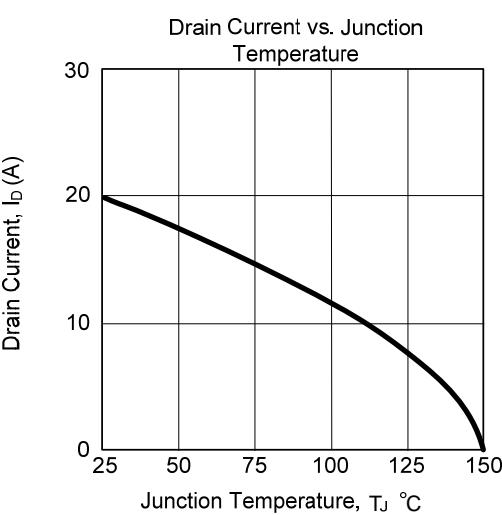
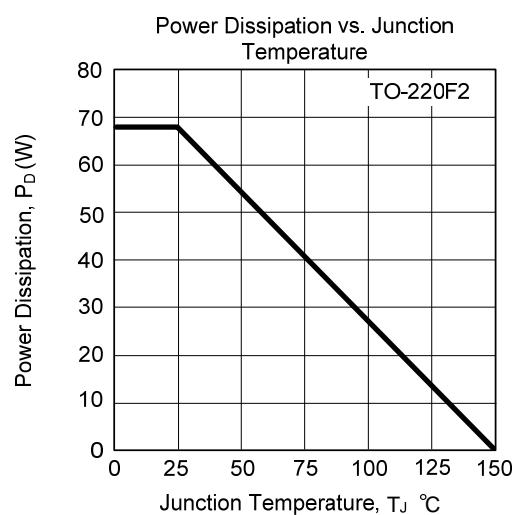
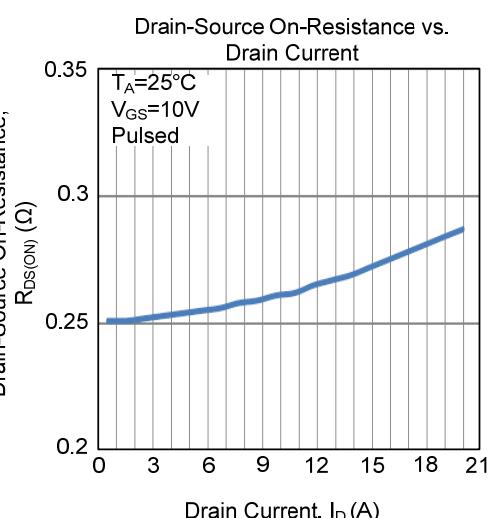
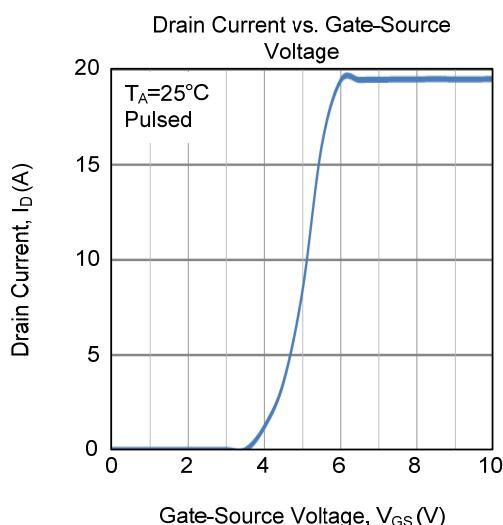
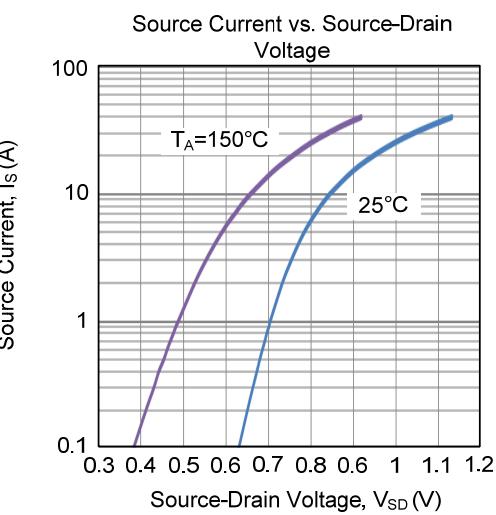
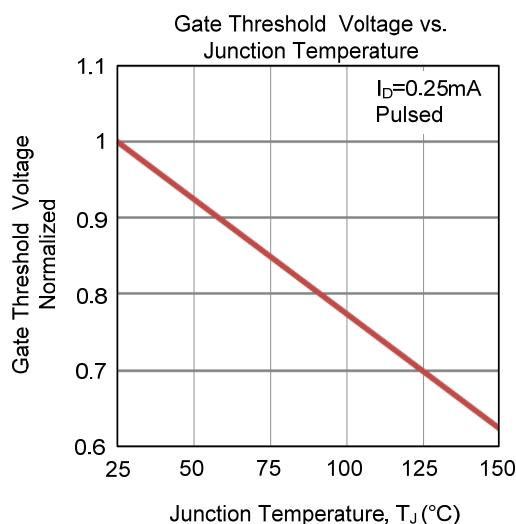


Unclamped Inductive Switching Waveforms

5. Typical Characteristics



5. Typical Characteristics(cont.)



6. Package Mechanical Data

TO-220 Package

